

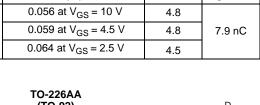
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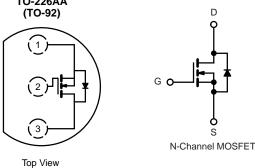
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www.din-tek.jp

# N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
	0.056 at V <sub>GS</sub> = 10 V	4.8				
20	0.059 at V <sub>GS</sub> = 4.5 V	4.8	7.9 nC			
	0.064 at V <sub>GS</sub> = 2.5 V	4.5				





#### **FEATURES**

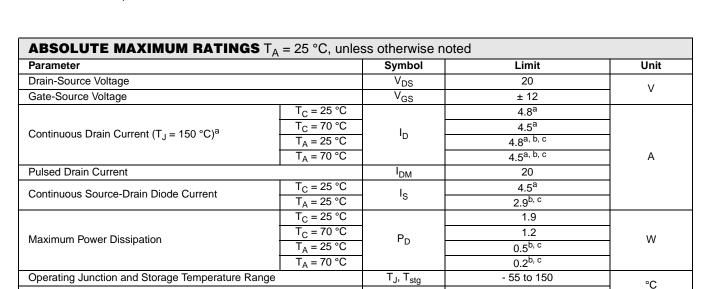
- · Halogen-free
- TrenchFET® Power MOSFET
- New Thermally Enhanced PowerPAK® SC-70 Package

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- Small Footprint Area
- Low On-Resistance
- 100 % R<sub>g</sub> Tested

#### **APPLICATIONS**

· Load Switch



THERMAL RESISTANCE RATINGS									
Parameter		Symbol	Typical	Maximum	Unit				
Maximum Junction-to-Ambient	t ≤ 5 s	R <sub>thJA</sub>	28	36	36 °C/W				
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	5.3	6.5	] 5/44				

## Notes:

- a. Package limited
- b. Surface Mounted on 1" x 1" FR4 board.

Soldering Recommendations (Peak Temperature)

c. t = 5 s.



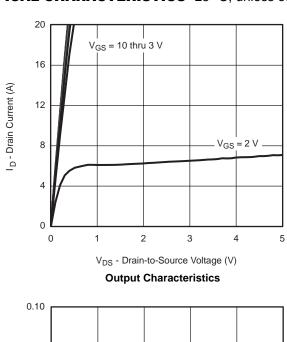
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static		-			1	L	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$ $\Delta V_{GS(th)}/T_{J}$			25		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient		I <sub>D</sub> = 250 μA		- 3.7			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.6		1.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			1	1	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le 5 \text{ V}, V_{GS} = 4.5 \text{ V}$		20		Α	
	,	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.8 A		0.056	0.062	+	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4.8 A		0.059	0.065	Ω	
		V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 4.8 A		0.064	0.070	1	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 4.8 A		20		S	
Dynamic <sup>b</sup>		-		L		II.	
Input Capacitance	C <sub>iss</sub>	ina		1020		T	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		160		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	D3 - 7 G3 - 7		70			
Treverse Transier Supusitation		V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.8 A		17.5	27	-	
Total Gate Charge	$egin{array}{c} Q_{ m g} & & & \\ Q_{ m gs} & & & \\ Q_{ m gd} & & & \end{array}$	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4.8 A		7.9	16	nC	
Gate-Source Charge				2.1			
Gate-Drain Charge				1.1			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.6	3	6	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	18		
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, R_1 = 1.3 \Omega$		11	17		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 3.9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		27	41		
Fall Time	t <sub>f</sub>	Ţ		11	17		
Turn-On Delay Time	t <sub>d(on)</sub>			7	14	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, R_{L} = 1.3 \Omega$		10	15		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 3.9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t <sub>f</sub>			8	16		
<b>Drain-Source Body Diode Characterist</b>	ics			<u>I</u>	<u> </u>	<u>I</u>	
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			4.5 <sup>c</sup>	A	
Pulse Diode Forward Current	I <sub>SM</sub>	-			20		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 3.9 A, V <sub>GS</sub> = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time t <sub>rr</sub>		2 33		16	24	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	†		6	12	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 7.9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		7	†	†	
Reverse Recovery Rise Time	t <sub>b</sub>	<b>-</b>		8		ns	

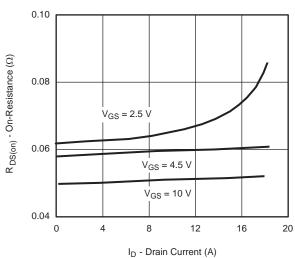
- a. Pulse test; pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.
- c. Package Limited

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

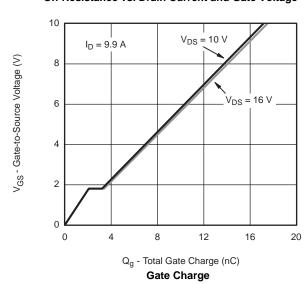


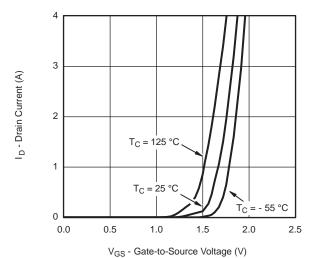
## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



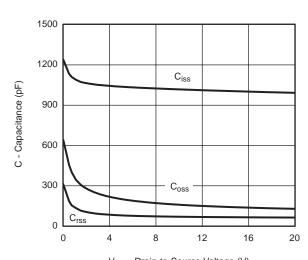




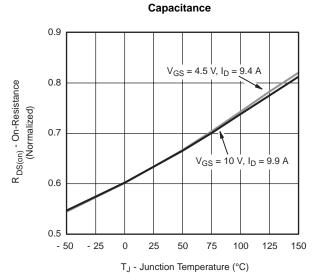




**Transfer Characteristics** 



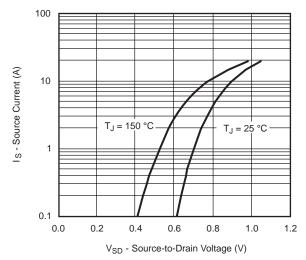
 $V_{\mbox{\footnotesize DS}}$  - Drain-to-Source Voltage (V)



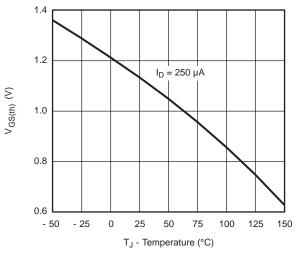
On-Resistance vs. Junction Temperature



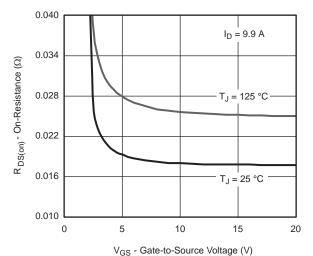
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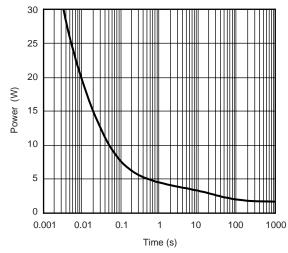
#### Soure-Drain Diode Forward Voltage



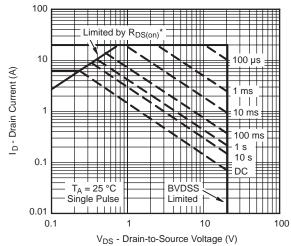
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage



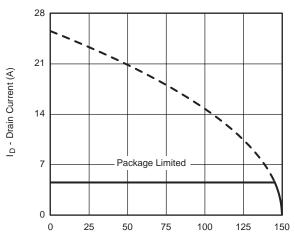
Single Pulse Power, Junction-to-Ambient



\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

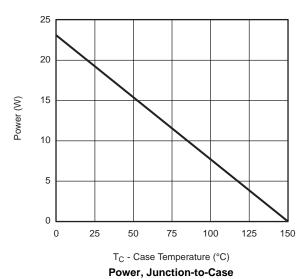
Safe Operating Area, Junction-to-Ambient

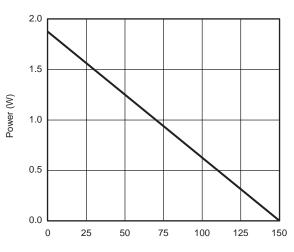
## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



T<sub>C</sub> - Case Temperature (°C)

### **Current Derating\***





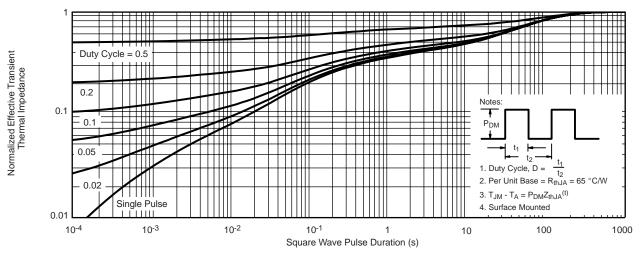
T<sub>A</sub> - Ambient Temperature (°C) **Power, Junction-to-Ambient** 

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

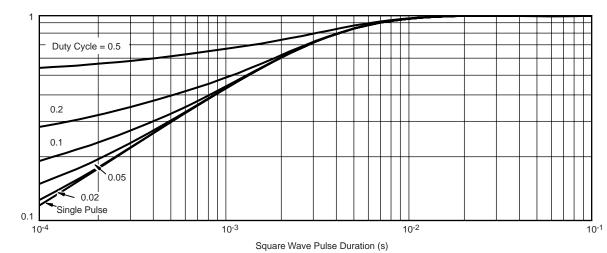


Normalized Effective Transient Thermal Impedance

## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



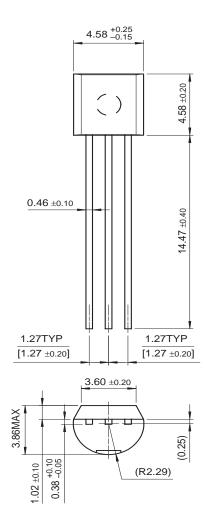
## Normalized Thermal Transient Impedance, Junction-to-Ambient

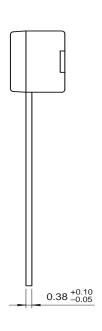


Normalized Thermal Transient Impedance, Junction-to-Case

## **Mechanical Dimensions**

TO-92









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